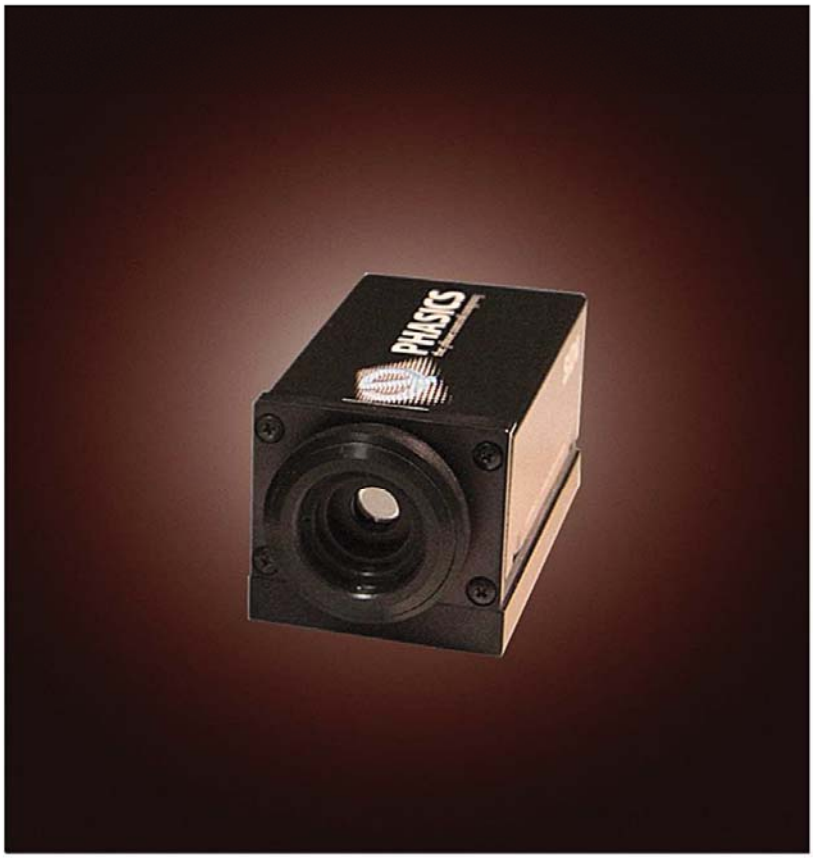
SID4-NIR
WAVE FRONT SENSOR



The SID4-NIR wavefront sensor covers the near infrared region from **1.5µm to 1.6µm**. Its patented technology offers very high resolution which ensures accurate measurement. It also offers compactness and ease of use.

For **laser metrology**, the SID4-NIR gives an exhaustive characterization: aberrations, M^2, intensity profiles, beam parameters...

For **lens testing**, the SID4-NIR is the perfect tool to characterize NIR objective lenses. It provides both wavefront aberrations and MTF in a single shot.

SPECIFICATIONS

Wavelength range	1.5 – 1.6 µm
Aperture dimension	3.6 x 4.8 mm²
Spatial resolution	29.6 µm
Phase & intensity sampling	160 x 120
Resolution (Phase)	< 11 nm RMS
Accuracy	15 nm RMS
Acquisition rate	> 60 fps
Real-time processing frequency	> 10 fps (full resolution)
Dimensions (w x h x l)	44 x 33 x 57.5 mm
Weight	~250 g

KEY FEATURES

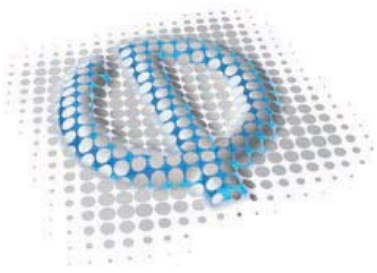
- Very high resolution (160 x 120)
- High NA measurement with no relay lens
- Compact and insensitive to vibration for easy integration in an optical bench
- Cost-effective solution for near infrared

PHASICS - The phase control company

Distribution in the UK & Ireland

Lambda

www.lambdaphoto.co.uk



Distribution in the UK & Ireland

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